



MOS INTEGRATED CIRCUIT

μ PD4264400, 4265400

64 M-BIT DYNAMIC RAM 16 M-WORD BY 4-BIT, FAST PAGE MODE

Description

The μ PD4264400, 4265400 are 16,777,216 words by 4 bits dynamic CMOS RAMs. The fast page mode capability realize high speed access and low power consumption.

These are packaged in 32-pin plastic TSOP(II) and 32-pin plastic SOJ.

Features

- 16,777,216 words by 4 bits organization
- Single +3.3 V \pm 0.3 V power supply
- Fast access and cycle time

Part number	Power consumption		Access time (MAX.)	R/W cycle time (MIN.)	Fast page mode cycle time (MIN.)
	Active (MAX.)	Standby(MAX.)			
μ PD4264400-A50	360 mW	1.80 mW (CMOS level input)	50 ns	90 ns	35 ns
μ PD4265400-A50	468 mW		60 ns	110 ns	40 ns
μ PD4264400-A60	324 mW				
μ PD4265400-A60	396 mW		70 ns	130 ns	45 ns
μ PD4264400-A70	288 mW				
μ PD4265400-A70	360 mW		80 ns	150 ns	50 ns
μ PD4264400-A80	252 mW				
μ PD4265400-A80	324 mW				

- $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh, $\overline{\text{RAS}}$ only refresh, Hidden refresh

Part number	Row address	Column address	Refresh	Refresh cycle
μ PD4264400	A0 - A12	A0 - A10	$\overline{\text{RAS}}$ only refresh, Normal read/write	8,192 cycles/64 ms
			$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh, Hidden refresh	4,096 cycles/64 ms
μ PD4265400	A0 - A11	A0 - A11	$\overline{\text{RAS}}$ only refresh, Normal read/write,	4,096 cycles/64 ms
			$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh, Hidden refresh	

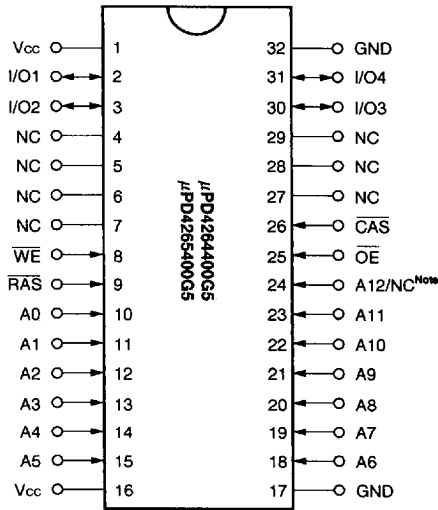
The information in this document is subject to change without notice.

Ordering Information

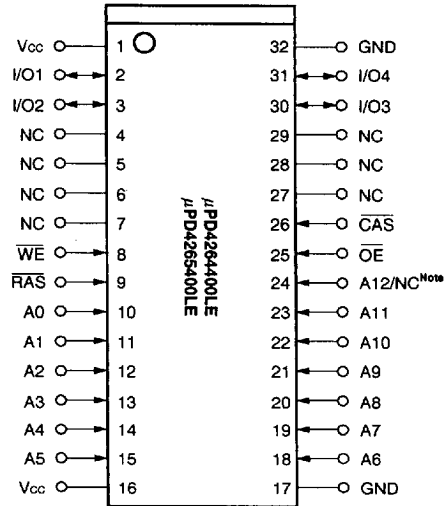
Part number	Access time (MAX.)	Package	Refresh
μPD4264400G5-A50	50 ns	32-pin plastic TSOP (II) (400 mil)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh $\overline{\text{RAS}}$ only refresh Hidden refresh
μPD4264400G5-A60	60 ns		
μPD4264400G5-A70	70 ns		
μPD4264400G5-A80	80 ns		
μPD4264400LE-A50	50 ns	32-pin plastic SOJ (400 mil)	
μPD4264400LE-A60	60 ns		
μPD4264400LE-A70	70 ns		
μPD4264400LE-A80	80 ns		
μPD4265400G5-A50	50 ns	32-pin plastic TSOP (II) (400 mil)	
μPD4265400G5-A60	60 ns		
μPD4265400G5-A70	70 ns		
μPD4265400G5-A80	80 ns		
μPD4265400LE-A50	50 ns	32-pin plastic SOJ (400 mil)	
μPD4265400LE-A60	60 ns		
μPD4265400LE-A70	70 ns		
μPD4265400LE-A80	80 ns		

Pin Configurations (Marking Side)

32-pin Plastic TSOP (II) (400 mil)



32-pin Plastic SOJ (400 mil)



Note A12 ... μPD4264400

NC ... μPD4265400

- A0 to A12 : Address Inputs
- I/O1 to I/O4 : Data Inputs/Outputs
- RAS : Row Address Strobe
- CAS : Column Address Strobe
- WE : Write Enable
- OE : Output Enable
- Vcc : Power Supply
- GND : Ground
- NC : No Connection

Input/Output Pin Functions

The μPD4264400, 4265400 have input pins \overline{RAS} , \overline{CAS} , \overline{WE} , \overline{OE} , Address^{Note} and input/output pins I/O1 to I/O4.

Pin name	Input/Output	Function
\overline{RAS} (Row address strobe)	Input	\overline{RAS} activates the sense amplifier by latching a row address and selecting a corresponding word line. It refreshes memory cell array of one line selected by the row address. It also selects the following function. • \overline{CAS} before \overline{RAS} refresh
\overline{CAS} (Column address strobe)	Input	\overline{CAS} activates data input/output circuit by latching column address and selecting a digit line connected with the sense amplifier.
A0 to A _x ^{Note} (Address inputs)	Input	Address bus. Input total 24-bit of address signal, upper bits and lower bits ^{Note} in sequence (address multiplex method). Therefore, one word is selected from 16,777,216-word by 4-bit memory cell array. In actual operation, latch row address by specifying row address and activating \overline{RAS} . Then, switch the address bus to column address and activate \overline{CAS} . Each address is taken into the device when \overline{RAS} and \overline{CAS} are activated. Therefore, the address input setup time (t_{ASP} , t_{ASC}) and hold time (t_{RAH} , t_{CAH}) are specified for the activation of \overline{RAS} and \overline{CAS} .
\overline{WE} (Write enable)	Input	Write control signal. Write operation is executed by activating \overline{RAS} , \overline{CAS} and \overline{WE} .
\overline{OE} (Output enable)	Input	Read control signal. Read operation can be executed by activating \overline{RAS} , \overline{CAS} and \overline{OE} . If \overline{WE} is activated during read operation, \overline{OE} is to be ineffective in the device. Therefore, read operation cannot be executed.
I/O1 to I/O4 (Data inputs/outputs)	Input/Output	4-bit data bus. I/O1 to I/O4 are used to input/output data.

Note

Part number	Address inputs	Upper bits	Lower bits
μPD4264400	A0-A12	13	11
μPD4265400	A0-A11	12	12

Electrical Specifications (Preliminary)

- All voltages are referenced to GND.
- After power up ($V_{CC} \geq V_{CC(MIN.)}$), wait more than 100 μs (\overline{RAS} , \overline{CAS} inactive) and then, execute eight \overline{CAS} before \overline{RAS} or \overline{RAS} only refresh cycles as dummy cycles to initialize internal circuit.

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Voltage on any pin relative to GND	V_T		-0.5 to +4.6	V
Supply voltage	V_{CC}		-0.5 to +4.6	V
Output current	I_O		20	mA
Power dissipation	P_D		1	W
Operating ambient temperature	T_A		0 to +70	°C
Storage temperature	T_{sig}		-55 to +125	°C

Caution Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Supply voltage	V_{CC}		3.0	3.3	3.6	V
High level input voltage	V_{IH}		2.0		$V_{CC} + 0.3$	V
Low level input voltage	V_{IL}		-0.3		+0.8	V
Operating ambient temperature	T_A		0		70	°C

Capacitance ($T_A = 25\text{ °C}$, $f = 1\text{ MHz}$)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	C_{i1}	Address			5	pF
	C_{i2}	\overline{RAS} , \overline{CAS} , \overline{WE} , \overline{OE}			7	
Data input/output capacitance	C_{iO}	I/O			7	pF

DC Characteristics (Recommended operating conditions unless otherwise noted)

[μPD4264400]

Parameter	Symbol	Test condition	MIN.	MAX.	Unit	Notes
Operating current	I _{CC1}	$\overline{\text{RAS}}, \overline{\text{CAS}}$ Cycling $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.})$ $I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	100	mA	1, 2, 3
			$t_{\text{RAC}} = 60 \text{ ns}$	90		
			$t_{\text{RAC}} = 70 \text{ ns}$	80		
			$t_{\text{RAC}} = 80 \text{ ns}$	70		
Standby current	I _{CC2}	$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{\text{IH}}(\text{MIN.}), I_o = 0 \text{ mA}$ $\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{\text{CC}} - 0.2 \text{ V}, I_o = 0 \text{ mA}$		1.0	mA	
				0.5		
RAS only refresh current	I _{CC3}	$\overline{\text{RAS}}$ Cycling, $\overline{\text{CAS}} \geq V_{\text{IH}}(\text{MIN.})$ $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.}), I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	100	mA	1, 2, 3, 4
			$t_{\text{RAC}} = 60 \text{ ns}$	90		
			$t_{\text{RAC}} = 70 \text{ ns}$	80		
			$t_{\text{RAC}} = 80 \text{ ns}$	70		
Operating current (Fast page mode)	I _{CC4}	$\overline{\text{RAS}} \leq V_{\text{IL}}(\text{MAX.}), \overline{\text{CAS}}$ Cycling $t_{\text{PC}} = t_{\text{PC}}(\text{MIN.}), I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	80	mA	1, 2, 5
			$t_{\text{RAC}} = 60 \text{ ns}$	70		
			$t_{\text{RAC}} = 70 \text{ ns}$	60		
			$t_{\text{RAC}} = 80 \text{ ns}$	50		
CAS before RAS refresh current	I _{CC5}	$\overline{\text{RAS}}$ Cycling $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.})$ $I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	130	mA	1, 2
			$t_{\text{RAC}} = 60 \text{ ns}$	110		
			$t_{\text{RAC}} = 70 \text{ ns}$	100		
			$t_{\text{RAC}} = 80 \text{ ns}$	90		
Input leakage current	I _{I(L)}	$V_i = 0 \text{ to } 3.6 \text{ V}$ All other pins not under test = 0 V	-5	+5	μA	
Output leakage current	I _{O(L)}	$V_o = 0 \text{ to } 3.6 \text{ V}$ Output is disabled (Hi-Z)	-5	+5	μA	
High level output voltage	V _{OH}	$I_o = -2.0 \text{ mA}$	2.4		V	
Low level output voltage	V _{OL}	$I_o = +2.0 \text{ mA}$		0.4	V	

[μPD4265400]

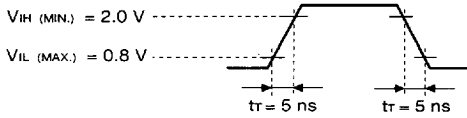
Parameter	Symbol	Test condition	MIN.	MAX.	Unit	Notes
Operating current	I _{CC1}	$\overline{RAS}, \overline{CAS}$ Cycling $t_{RC} = t_{RC(MIN.)}$ $I_O = 0 \text{ mA}$	$t_{RAC} = 50 \text{ ns}$	130	mA	1, 2, 3
			$t_{RAC} = 60 \text{ ns}$	110		
			$t_{RAC} = 70 \text{ ns}$	100		
			$t_{RAC} = 80 \text{ ns}$	90		
Standby current	I _{CC2}	$\overline{RAS}, \overline{CAS} \geq V_{IH(MIN.)}, I_O = 0 \text{ mA}$		1.0	mA	
		$\overline{RAS}, \overline{CAS} \geq V_{CC} - 0.2 \text{ V}, I_O = 0 \text{ mA}$		0.5		
RAS only refresh current	I _{CC3}	\overline{RAS} Cycling, $\overline{CAS} \geq V_{IH(MIN.)}$ $t_{RC} = t_{RC(MIN.)}, I_O = 0 \text{ mA}$	$t_{RAC} = 50 \text{ ns}$	130	mA	1, 2, 3, 4
			$t_{RAC} = 60 \text{ ns}$	110		
			$t_{RAC} = 70 \text{ ns}$	100		
			$t_{RAC} = 80 \text{ ns}$	90		
Operating current (Fast page mode)	I _{CC4}	$\overline{RAS} \leq V_{IL(MAX.)}, \overline{CAS}$ Cycling $t_{PC} = t_{PC(MIN.)}, I_O = 0 \text{ mA}$	$t_{RAC} = 50 \text{ ns}$	80	mA	1, 2, 5
			$t_{RAC} = 60 \text{ ns}$	70		
			$t_{RAC} = 70 \text{ ns}$	60		
			$t_{RAC} = 80 \text{ ns}$	50		
CAS before \overline{RAS} refresh current	I _{CC5}	\overline{RAS} Cycling $t_{RC} = t_{RC(MIN.)}$ $I_O = 0 \text{ mA}$	$t_{RAC} = 50 \text{ ns}$	130	mA	1, 2
			$t_{RAC} = 60 \text{ ns}$	110		
			$t_{RAC} = 70 \text{ ns}$	100		
			$t_{RAC} = 80 \text{ ns}$	90		
Input leakage current	I _{I(L)}	$V_I = 0 \text{ to } 3.6 \text{ V}$ All other pins not under test = 0 V	-5	+5	μA	
Output leakage current	I _{O(L)}	$V_O = 0 \text{ to } 3.6 \text{ V}$ Output is disabled (Hi-Z)	-5	+5	μA	
High level output voltage	V _{OH}	$I_O = -2.0 \text{ mA}$	2.4		V	
Low level output voltage	V _{OL}	$I_O = +2.0 \text{ mA}$		0.4	V	

- Notes**
- I_{CC1}, I_{CC3}, I_{CC4} and I_{CC5} depend on cycle rates (t_{RC} and t_{PC}).
 - Specified values are obtained with outputs unloaded.
 - I_{CC1} and I_{CC3} are measured assuming that address can be changed once or less during $\overline{RAS} \leq V_{IL(MAX.)}$ and $\overline{CAS} \geq V_{IH(MIN.)}$.
 - I_{CC3} is measured assuming that all column address inputs are held at either high or low.
 - I_{CC4} is measured assuming that all column address inputs are switched only once during each fast page cycle.

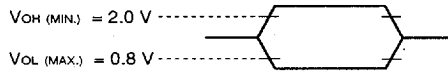
AC Characteristics (Recommended Operating Conditions unless otherwise noted)

AC Characteristics Test Conditions

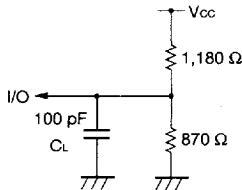
(1) Input timing specification



(2) Output timing specification



(3) Output load condition



Common to Read, Write, Read Modify Write Cycle

Parameter	Symbol	trac = 50 ns		trac = 60 ns		trac = 70 ns		trac = 80 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read / Write cycle time	t _{RC}	90	–	110	–	130	–	150	–	ns	
$\overline{\text{RAS}}$ precharge time	t _{RP}	30	–	40	–	50	–	60	–	ns	
$\overline{\text{CAS}}$ precharge time	t _{CPN}	8	–	10	–	10	–	10	–	ns	
$\overline{\text{RAS}}$ pulse width	t _{RAS}	50	10,000	60	10,000	70	10,000	80	10,000	ns	
$\overline{\text{CAS}}$ pulse width	t _{CAS}	13	10,000	15	10,000	18	10,000	20	10,000	ns	
$\overline{\text{RAS}}$ hold time	t _{RSH}	13	–	15	–	18	–	20	–	ns	
$\overline{\text{CAS}}$ hold time	t _{CSH}	50	–	60	–	70	–	80	–	ns	
$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ delay time	t _{RCd}	18	37	20	45	20	52	25	60	ns	1
$\overline{\text{RAS}}$ to column address delay time	t _{RAD}	13	25	15	30	15	35	17	40	ns	1
$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ precharge time	t _{CRP}	5	–	5	–	5	–	5	–	ns	2
Row address setup time	t _{ASR}	0	–	0	–	0	–	0	–	ns	
Row address hold time	t _{RAH}	8	–	10	–	10	–	12	–	ns	
Column address setup time	t _{ASC}	0	–	0	–	0	–	0	–	ns	
Column address hold time	t _{CAH}	13	–	15	–	15	–	15	–	ns	
$\overline{\text{OE}}$ lead time referenced to $\overline{\text{RAS}}$	t _{OES}	0	–	0	–	0	–	0	–	ns	
$\overline{\text{CAS}}$ to data setup time	t _{CLZ}	0	–	0	–	0	–	0	–	ns	
$\overline{\text{OE}}$ to data setup time	t _{OLZ}	0	–	0	–	0	–	0	–	ns	
$\overline{\text{OE}}$ to data delay time	t _{OED}	10	–	13	–	15	–	15	–	ns	
Transition time (rise and fall)	t _r	3	50	3	50	3	50	3	50	ns	
Refresh time	t _{REF}	–	64	–	64	–	64	–	64	ms	

Notes 1. For read cycles, access time is defined as follows:

Input conditions	Access time	Access time from $\overline{\text{RAS}}$
$t_{\text{RAD}} \leq t_{\text{RAD}}(\text{MAX.})$ and $t_{\text{RCD}} \leq t_{\text{RCD}}(\text{MAX.})$	$t_{\text{RAC}}(\text{MAX.})$	$t_{\text{RAC}}(\text{MAX.})$
$t_{\text{RAD}} > t_{\text{RAD}}(\text{MAX.})$ and $t_{\text{RCD}} \leq t_{\text{RCD}}(\text{MAX.})$	$t_{\text{AA}}(\text{MAX.})$	$t_{\text{RAD}} + t_{\text{AA}}(\text{MAX.})$
$t_{\text{RCD}} > t_{\text{RCD}}(\text{MAX.})$	$t_{\text{CAC}}(\text{MAX.})$	$t_{\text{RCD}} + t_{\text{CAC}}(\text{MAX.})$

$t_{\text{RAD}}(\text{MAX.})$ and $t_{\text{RCD}}(\text{MAX.})$ are specified as reference points only; they are not restrictive operating parameters. They are used to determine which access time (t_{RAC} , t_{AA} or t_{CAC}) is to be used for finding out when data will be available. Therefore, the input conditions $t_{\text{RAD}} \geq t_{\text{RAD}}(\text{MAX.})$ and $t_{\text{RCD}} \geq t_{\text{RCD}}(\text{MAX.})$ will not cause any operation problems.

2. $t_{\text{CRP}}(\text{MIN.})$ requirement is applied to $\overline{\text{RAS}}$, $\overline{\text{CAS}}$ cycles.

Read Cycle

Parameter	Symbol	$t_{\text{RAC}} = 50 \text{ ns}$		$t_{\text{RAC}} = 60 \text{ ns}$		$t_{\text{RAC}} = 70 \text{ ns}$		$t_{\text{RAC}} = 80 \text{ ns}$		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Access time from $\overline{\text{RAS}}$	t_{RAC}	-	50	-	60	-	70	-	80	ns	1
Access time from $\overline{\text{CAS}}$	t_{CAC}	-	13	-	15	-	18	-	20	ns	1
Access time from column address	t_{AA}	-	25	-	30	-	35	-	40	ns	1
Access time from $\overline{\text{OE}}$	t_{OEA}	-	13	-	15	-	18	-	20	ns	
Column address lead time referenced to $\overline{\text{RAS}}$	t_{RAL}	25	-	30	-	35	-	40	-	ns	
Read command setup time	t_{RCS}	0	-	0	-	0	-	0	-	ns	
Read command hold time referenced to $\overline{\text{RAS}}$	t_{RRH}	0	-	0	-	0	-	0	-	ns	2
Read command hold time referenced to $\overline{\text{CAS}}$	t_{RCH}	0	-	0	-	0	-	0	-	ns	2
Output buffer turn-off delay time from $\overline{\text{OE}}$	t_{OEZ}	0	10	0	13	0	15	0	15	ns	3
Output buffer turn-off delay time from $\overline{\text{CAS}}$	t_{OFF}	0	10	0	13	0	15	0	15	ns	3

Notes 1. For read cycles, access time is defined as follows:

Input conditions	Access time	Access time from $\overline{\text{RAS}}$
$t_{\text{RAD}} \leq t_{\text{RAD}}(\text{MAX.})$ and $t_{\text{RCD}} \leq t_{\text{RCD}}(\text{MAX.})$	$t_{\text{RAC}}(\text{MAX.})$	$t_{\text{RAC}}(\text{MAX.})$
$t_{\text{RAD}} > t_{\text{RAD}}(\text{MAX.})$ and $t_{\text{RCD}} \leq t_{\text{RCD}}(\text{MAX.})$	$t_{\text{AA}}(\text{MAX.})$	$t_{\text{RAD}} + t_{\text{AA}}(\text{MAX.})$
$t_{\text{RCD}} > t_{\text{RCD}}(\text{MAX.})$	$t_{\text{CAC}}(\text{MAX.})$	$t_{\text{RCD}} + t_{\text{CAC}}(\text{MAX.})$

$t_{\text{RAD}}(\text{MAX.})$ and $t_{\text{RCD}}(\text{MAX.})$ are specified as reference points only; they are not restrictive operating parameters. They are used to determine which access time (t_{RAC} , t_{AA} or t_{CAC}) is to be used for finding out when output data will be available. Therefore, the input conditions $t_{\text{RAD}} \geq t_{\text{RAD}}(\text{MAX.})$ and $t_{\text{RCD}} \geq t_{\text{RCD}}(\text{MAX.})$ will not cause any operation problems.

2. Either $t_{\text{RCH}}(\text{MIN.})$ or $t_{\text{RRH}}(\text{MIN.})$ should be met in read cycles.

3. $t_{\text{OFF}}(\text{MAX.})$ and $t_{\text{OEZ}}(\text{MAX.})$ define the time when the output achieves the condition of Hi-Z and is not referenced to V_{OH} or V_{OL} .

Write Cycle

Parameter	Symbol	t _{rac} = 50 ns		t _{rac} = 60 ns		t _{rac} = 70 ns		t _{rac} = 80 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
\overline{WE} hold time referenced to \overline{CAS}	twch	8	-	10	-	10	-	15	-	ns	1
\overline{WE} pulse width	twp	8	-	10	-	10	-	15	-	ns	1
\overline{WE} lead time referenced to \overline{RAS}	trwl	13	-	15	-	15	-	15	-	ns	
\overline{WE} lead time referenced to \overline{CAS}	tcwl	13	-	15	-	15	-	15	-	ns	
\overline{WE} setup time	twcs	0	-	0	-	0	-	0	-	ns	2
\overline{OE} hold time	toeh	0	-	0	-	0	-	0	-	ns	
Data-in setup time	t _{ds}	0	-	0	-	0	-	0	-	ns	3
Data-in hold time	t _{dh}	10	-	10	-	15	-	15	-	ns	3

- Notes**
1. t_{wp} (MIN.) is applied to late write cycles or read modify write cycles. In early write cycles, twch (MIN.) should be met.
 2. If twcs ≥ twcs (MIN.), the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle.
 3. t_{ds} (MIN.) and t_{dh} (MIN.) are referenced to the \overline{CAS} falling edge in early write cycles. In late write cycles and read modify write cycles, they are referenced to the \overline{WE} falling edge.

Read Modify Write Cycle

Parameter	Symbol	t _{rac} = 50 ns		t _{rac} = 60 ns		t _{rac} = 70 ns		t _{rac} = 80 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read modify write cycle time	trwc	128	-	153	-	175	-	195	-	ns	
\overline{RAS} to \overline{WE} delay time	trwd	70	-	83	-	95	-	105	-	ns	1
\overline{CAS} to \overline{WE} delay time	tcwd	33	-	38	-	43	-	45	-	ns	1
Column address to \overline{WE} delay time	tawd	45	-	53	-	60	-	65	-	ns	1

- Note**
1. If twcs ≥ twcs (MIN.), the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle. If trwd ≥ trwd (MIN.), tcwd ≥ tcwd (MIN.), tawd ≥ tawd (MIN.) and tcpwd ≥ tcpwd (MIN.), the cycle is a read modify write cycle and the data out will contain data read from the selected cell. If neither of the above conditions is met, the state of the data out is indeterminate.

Fast Page Mode

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		t _{RAC} = 80 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Fast page mode cycle time	t _{PC}	35	-	40	-	45	-	50	-	ns	
Access time from $\overline{\text{CAS}}$ precharge	t _{ACP}	-	30	-	35	-	40	-	45	ns	
RAS pulse width	t _{RASP}	50	125,000	60	125,000	70	125,000	80	125,000	ns	
CAS precharge time	t _{CP}	8	-	10	-	10	-	10	-	ns	
RAS hold time from $\overline{\text{CAS}}$ precharge	t _{RHCP}	30	-	35	-	40	-	45	-	ns	
Read modify write cycle time	t _{PRWC}	73	-	83	-	90	-	95	-	ns	
CAS precharge to $\overline{\text{WE}}$ delay time	t _{CPWD}	50	-	58	-	65	-	70	-	ns	1

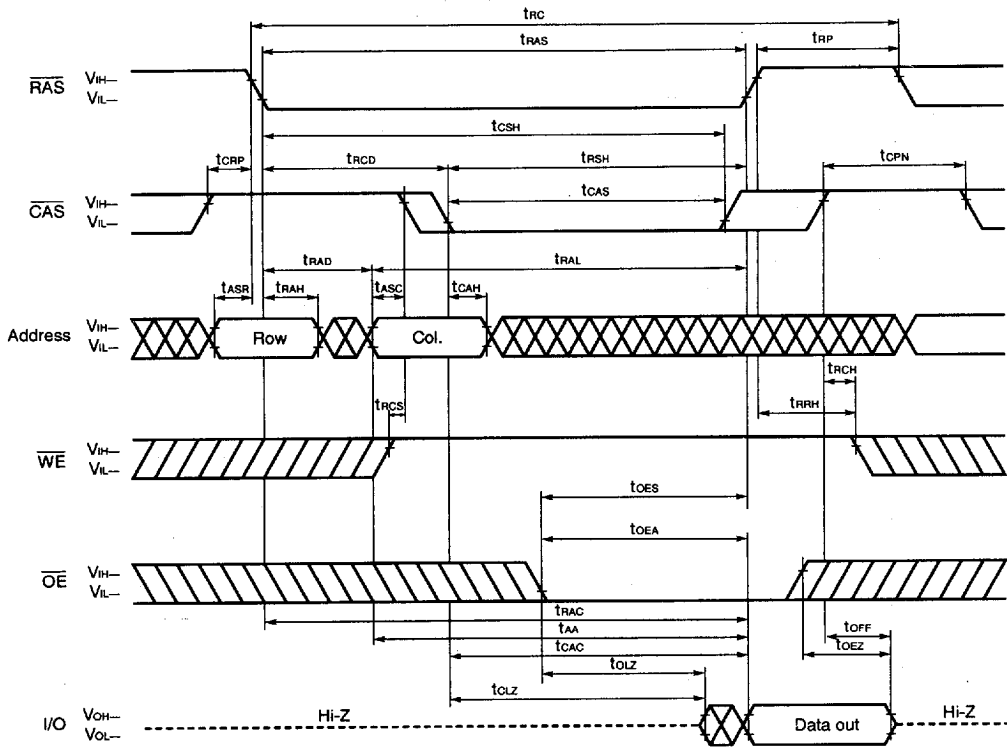
Note 1. If $t_{\text{WCS}} \geq t_{\text{WCS}}(\text{MIN.})$, the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle. If $t_{\text{RWD}} \geq t_{\text{RWD}}(\text{MIN.})$, $t_{\text{CWD}} \geq t_{\text{CWD}}(\text{MIN.})$, $t_{\text{AWD}} \geq t_{\text{AWD}}(\text{MIN.})$ and $t_{\text{CPWD}} \geq t_{\text{CPWD}}(\text{MIN.})$, the cycle is a read modify write cycle and the data out will contain data read from the selected cell. If neither of the above conditions is met, the state of the data out is indeterminate.

Refresh Cycle

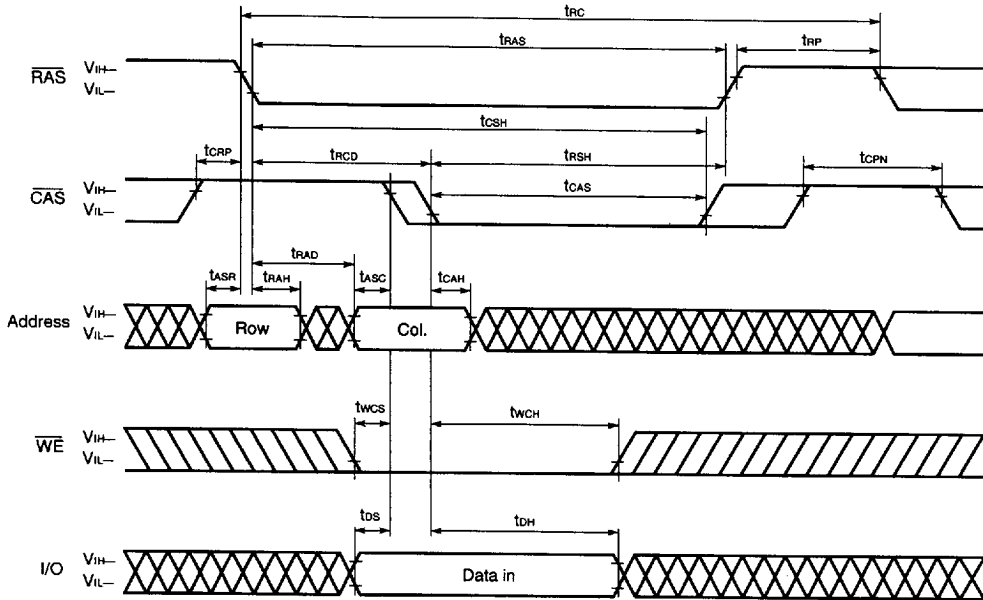
Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		t _{RAC} = 80 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
CAS setup time	t _{CSR}	5	-	5	-	5	-	5	-	ns	
$\overline{\text{CAS}}$ hold time ($\overline{\text{CAS}}$ before RAS refresh)	t _{CHR}	10	-	10	-	10	-	10	-	ns	
RAS precharge $\overline{\text{CAS}}$ hold time	t _{RPC}	5	-	5	-	5	-	5	-	ns	
$\overline{\text{WE}}$ setup time	t _{WSR}	10	-	10	-	10	-	10	-	ns	
$\overline{\text{WE}}$ hold time	t _{WHR}	15	-	15	-	15	-	15	-	ns	

■ 6427525 0091408 243 ■

Read Cycle

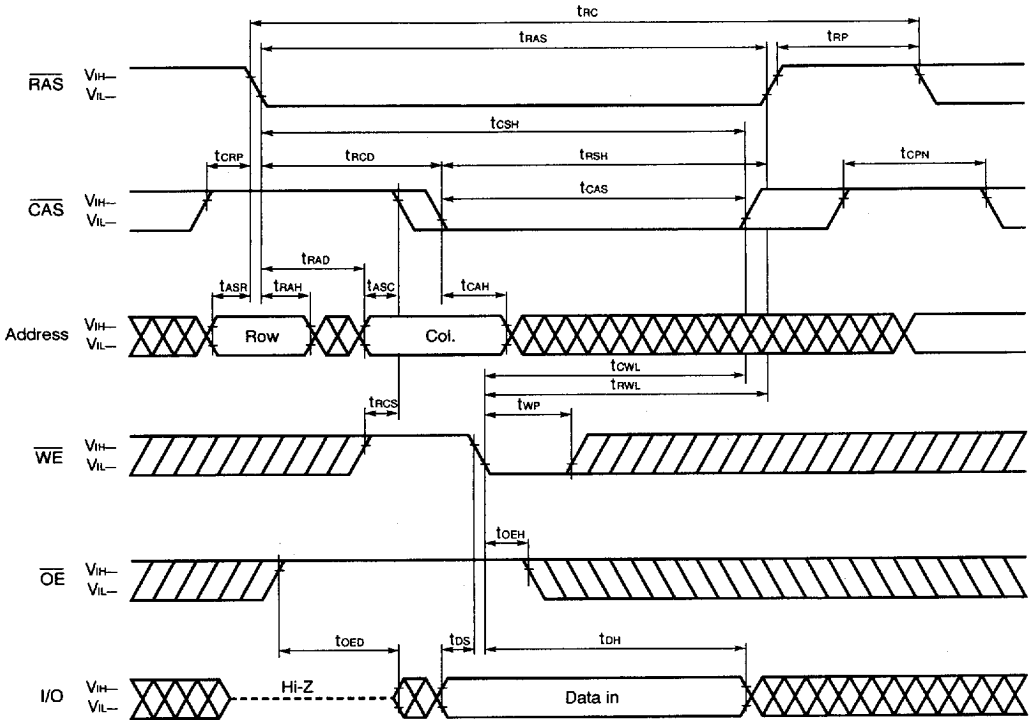


Early Write Cycle

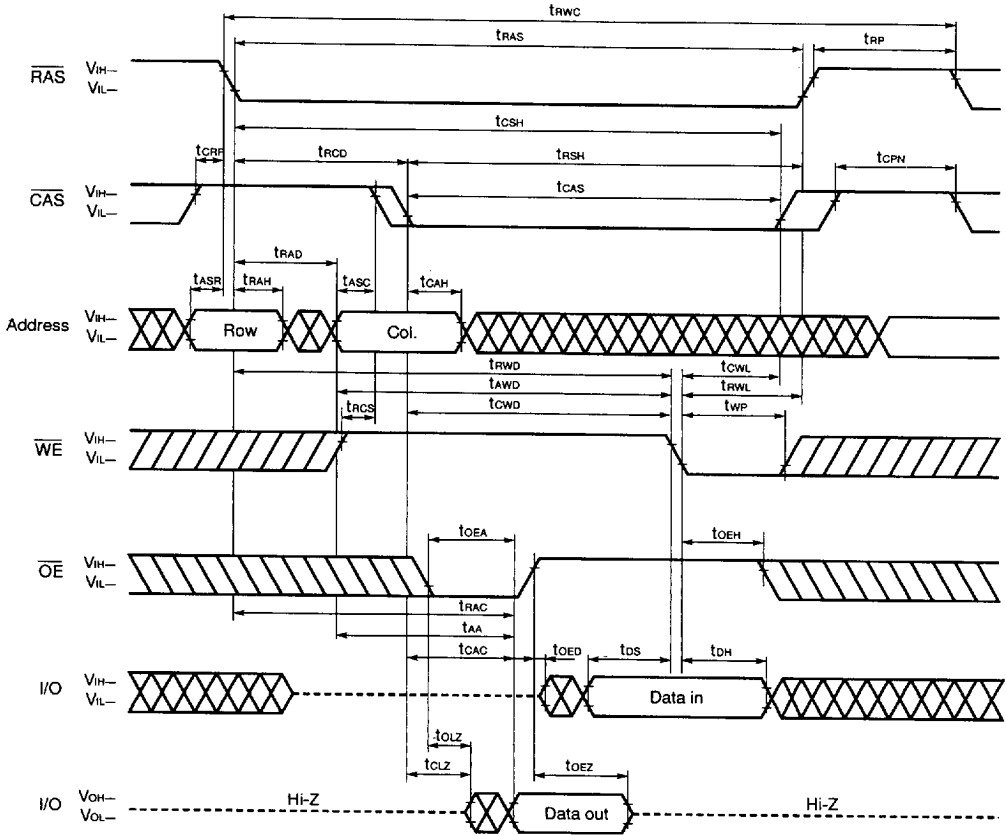


Remark $\overline{\text{OE}}$: Don't care

Late Write Cycle

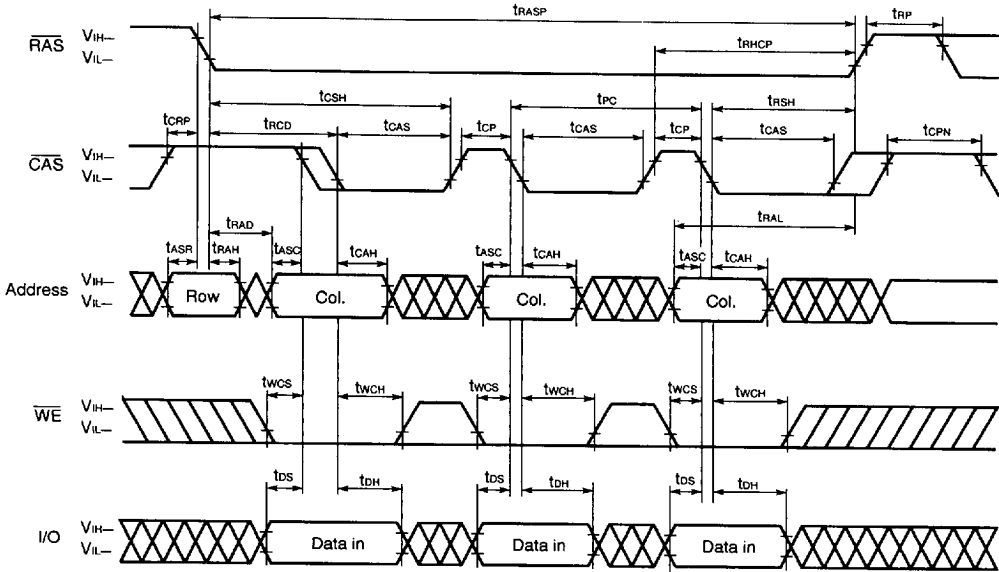


Read Modify Write Cycle



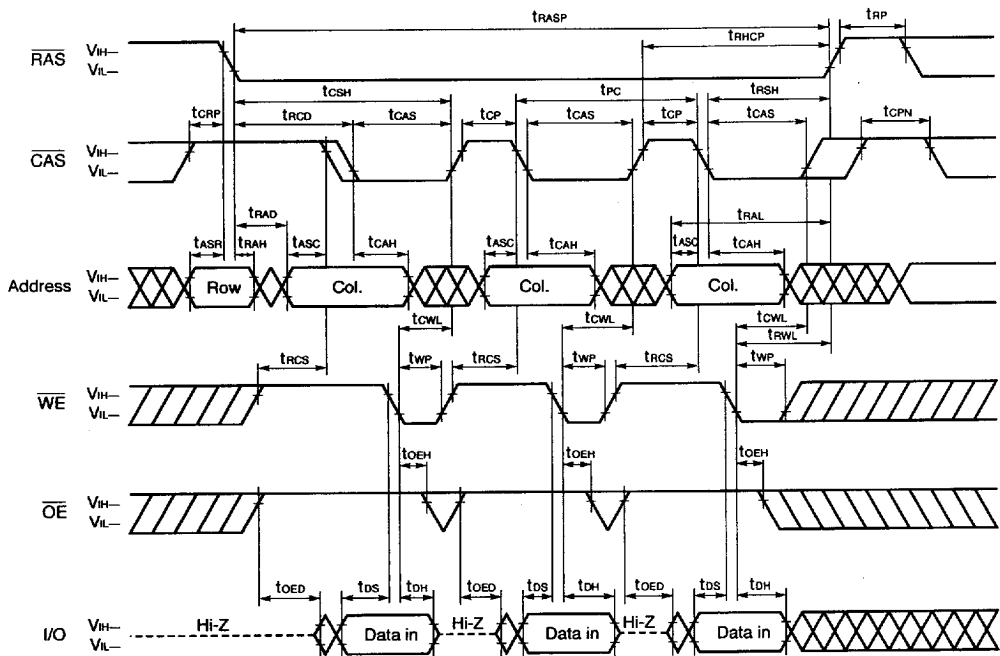
6427525 0091412 774

Fast Page Mode Early Write Cycle



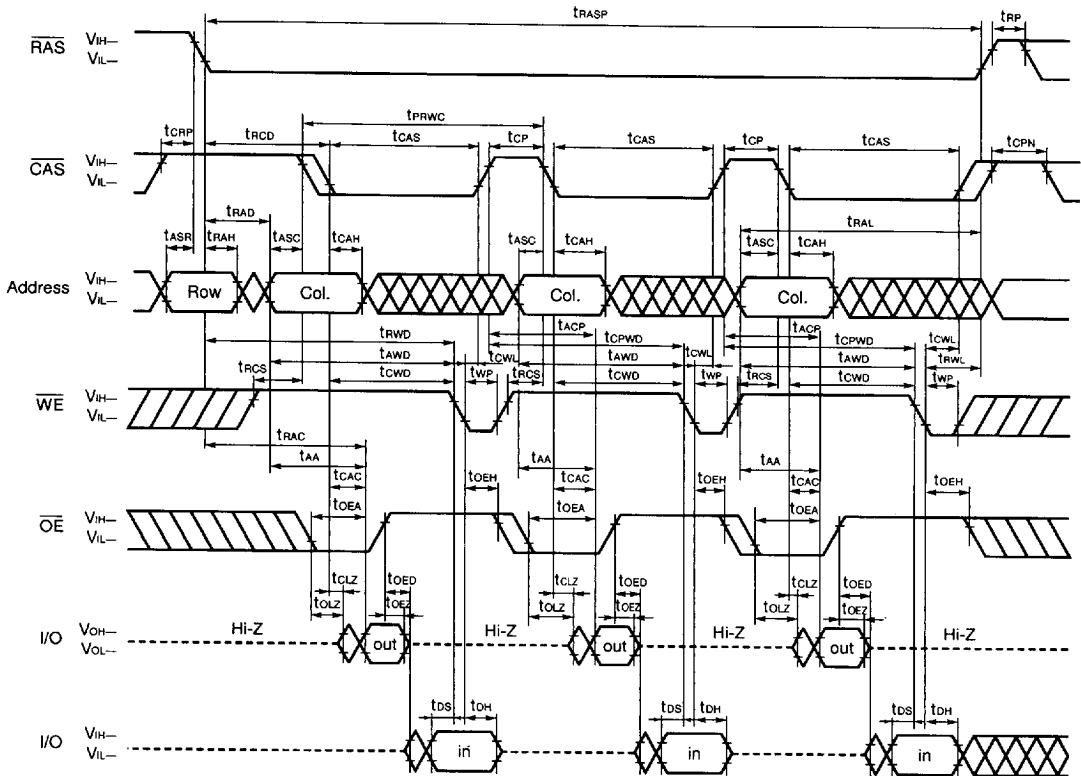
- Remarks**
1. \overline{OE} : Don't care
 2. In the fast page mode, read, write and read modify write cycles are available for each of the consecutive CAS cycles within the same \overline{RAS} cycle.

Fast Page Mode Late Write Cycle



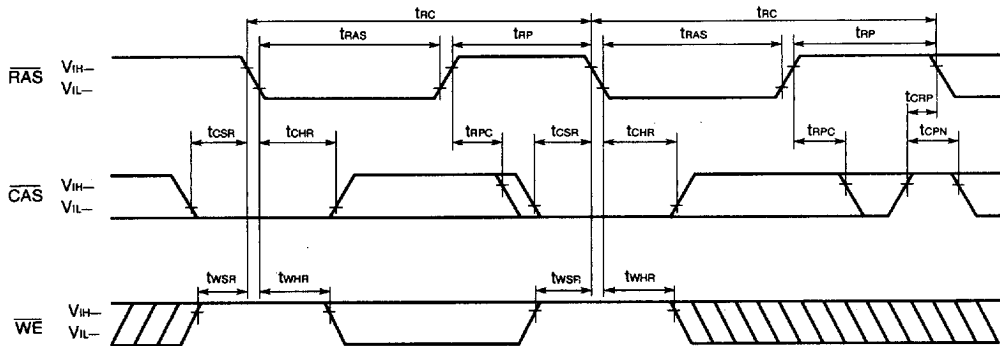
Remark In the fast page mode, read, write and read modify write cycles are available for each of the consecutive CAS cycles within the same RAS cycle.

Fast Page Mode Read Modify Write Cycle



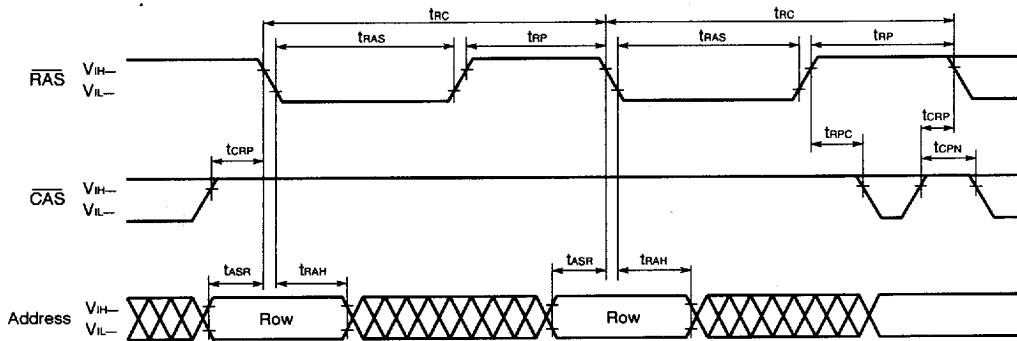
Remark In the fast page mode, read, write and read modify write cycles are available for each of the consecutive CAS cycles within the same RAS cycle.

CAS Before RAS Refresh Cycle



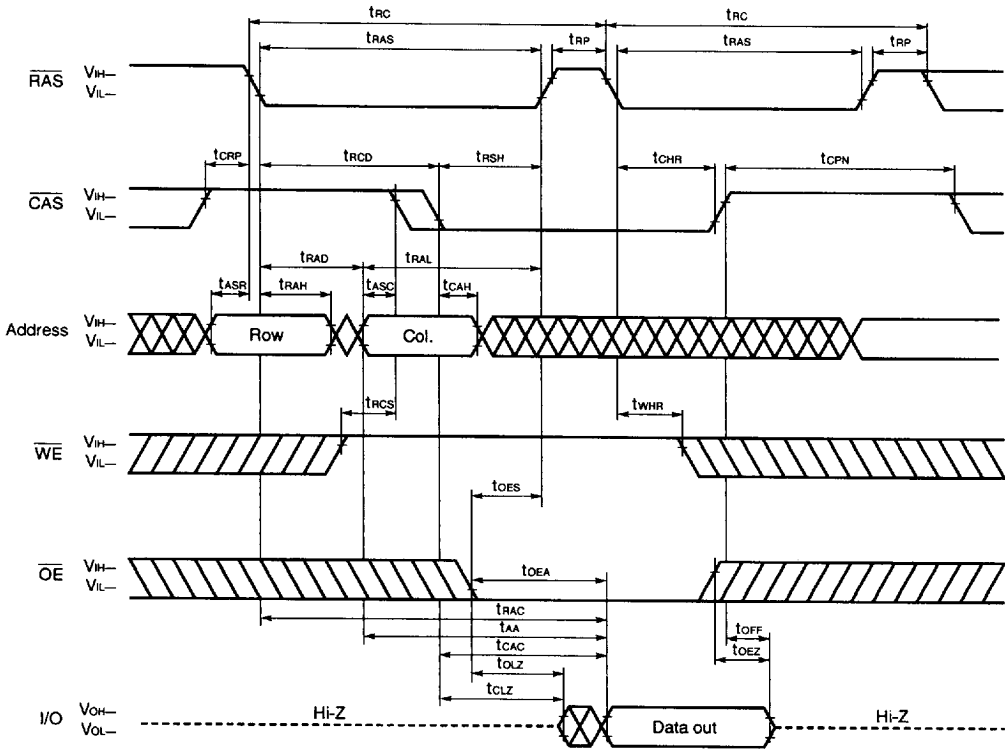
Remark Address, \overline{OE} : Don't care I/O: Hi-Z

RAS Only Refresh Cycle

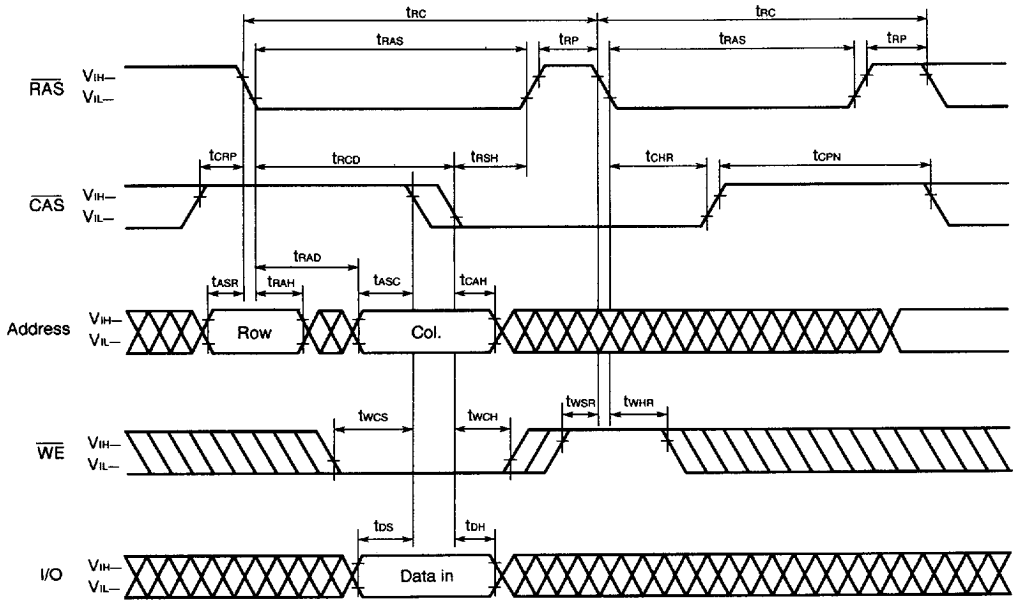


Remark \overline{WE} , \overline{OE} : Don't care I/O: Hi-Z

Hidden Refresh Cycle (Read)



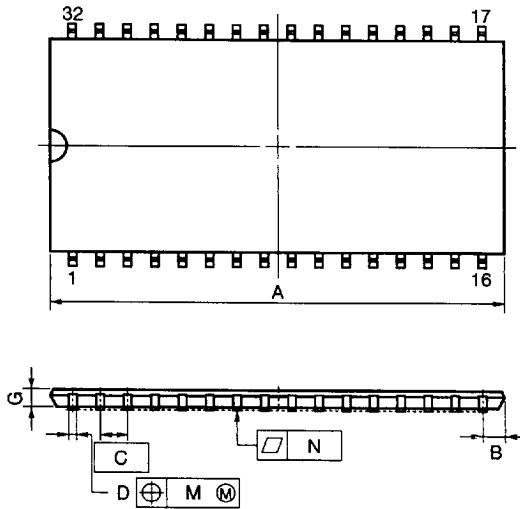
Hidden Refresh Cycle (Write)



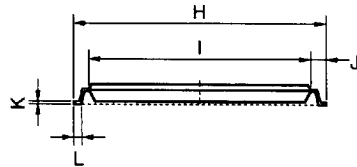
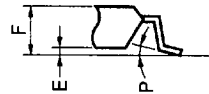
Remark \overline{OE} : Don't care

Package Drawings

32PIN PLASTIC TSOP(II) (400 mil)



detail of lead end



NOTE

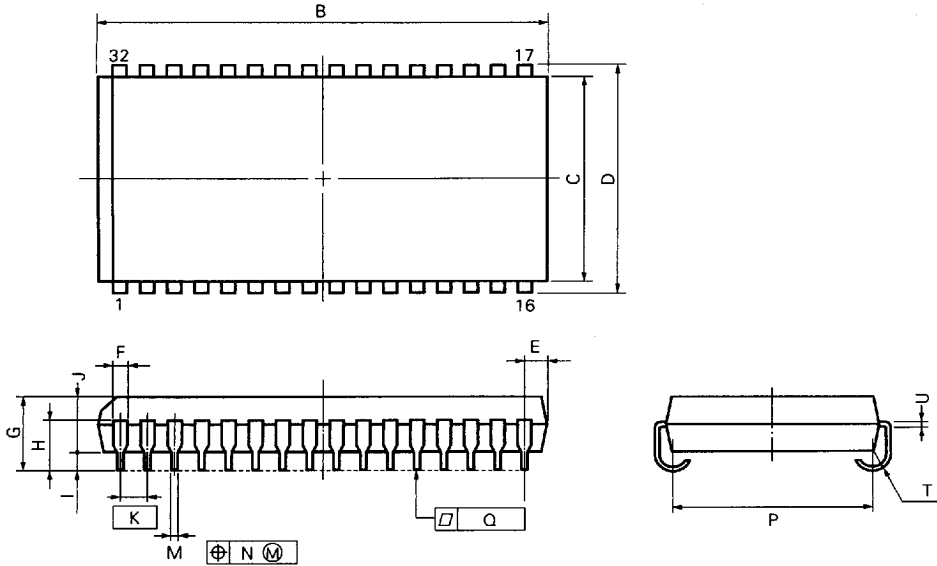
Each lead centerline is located within 0.21 mm (0.009 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	21.17 MAX.	0.834 MAX.
B	1.075 MAX.	0.043 MAX.
C	1.27 (T.P.)	0.050 (T.P.)
D	0.42 ^{+0.08} _{-0.07}	0.017±0.003
E	0.1±0.05	0.004±0.002
F	1.2 MAX.	0.048 MAX.
G	0.97	0.038
H	11.76±0.2	0.463±0.008
I	10.16±0.1	0.400±0.004
J	0.8±0.2	0.031 ^{+0.009} _{-0.008}
K	0.145 ^{+0.025} _{-0.015}	0.006±0.001
L	0.5±0.1	0.020 ^{+0.004} _{-0.005}
M	0.21	0.009
N	0.10	0.004
P	3° ^{+7°} _{-3°}	3° ^{+7°} _{-3°}

S32G5-50-7JD2

6427525 0091420 840

32 PIN PLASTIC SOJ (400 mil)



NOTE

Each lead centerline is located within 0.12 mm (0.005 inch) of its true position (T.P.) at maximum material condition.

P32LE-400A

ITEM	MILLIMETERS	INCHES
B	21.06±0.2	0.829±0.008
C	10.16	0.400
D	11.18±0.2	0.440±0.008
E	1.005±0.1	0.040 ^{+0.004} _{-0.005}
F	0.74	0.029
G	3.5±0.2	0.138±0.008
H	2.545±0.2	0.100±0.008
I	0.8 MIN.	0.031 MIN.
J	2.6	0.102
K	1.27 (T.P.)	0.050 (T.P.)
M	0.40±0.10	0.016 ^{+0.004} _{-0.005}
N	0.12	0.005
P	9.4±0.20	0.370±0.008
Q	0.1	0.004
T	R 0.85	R 0.033
U	0.20 ^{+0.10} _{-0.05}	0.008 ^{+0.004} _{-0.002}